

Notice of References Cited	Application/Control No. 09/127,364	Applicant(s)/Patent Under Reexamination YEDNOCK ET AL.	
	Examiner David Lukton	Art Unit 1653	Page 1 of 4

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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Notice of References Cited	Application/Control No. 09/127,364	Applicant(s)/Patent Under Reexamination YEDNOCK ET AL.	
	Examiner David Lukton	Art Unit 1653	Page 2 of 4

U.S. PATENT DOCUMENTS

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Notice of References Cited	Application/Control No. 09/127,364		Applicant(s)/Patent Under Reexamination YEDNOCK ET AL.	
	Examiner David Lukton		Art Unit 1653	Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	Examiner David Lukton	Art Unit 1653	Page 4 of 4

U.S. PATENT DOCUMENTS

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	C	US-			
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